



U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.		Serial No.		
				M-10697 US		09/697,025		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Applicant(s)				
(Use several sheets if necessary)				MEHRDAD NIKOONAHAD ET AL.				
				Filing Date		Group		
				October 26, 2000		2623		
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
28	AA	5,216,257	6/1/93	Brueck et al.				
	AB	5,712,707	1/27/98	Ausschnitt et al.				
	AC	5,757,507	5/26/98	Ausschnitt et al.				
	AD	5,923,041	7/13/99	Cresswell et al.				
	AE	6,130,750	10/10/00	Ausschnitt et al.				
	AF							
	AG							
	AH							
	AI							
	AJ							
AK								
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ	RECEIVED AUG 23 2001 Technology Center 2300						
	AR							
	AS							
Examiner	Date Considered		1/8/04					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.		Application No.	
				TNCR.183US0		09/697,025	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				Applicant(s)		Confirmation No.	
				Mehrdad Nikoonahad, et al.		3437	
				Filing Date		Group	
				October 26, 2000		2623	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
3/8	AA	4,871,955	10/03/89	Berger	318	640	
	AB	5,495,336	02/27/96	Nose et al.	356	375	
	AD						
	AE						
	AF						
	AG						
	AI						
	AJ						
	AD						
	AE						
	AF						
	AG						
	AK						
	AD						
	AE						
	AG						
	AH						
	AI						

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
3/8	AQ	R. Pfoff, et al., "In-Process Image Detecting Technique For Determination Of Overlay, And Image Quality For ASM-L Wafer Stepper", SPIE Vol. 1674 Optical/Laser Microlithography V (1992) pp. 594-608
Examiner	Date Considered 1/8/04	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.